

LM139JAN Low Power Low Offset Voltage Quad Comparators

Check for Samples: [LM139JAN](#)

FEATURES

- Wide Supply Voltage Range 5V to 36 V_{DC} or $\pm 2.5V$ to $\pm 18 V_{DC}$
- Very Low Supply Current Drain (0.8 mA) - Independent of Supply Voltage
- Low Input Biasing Current: 25 nA
- Low Input Offset Current: ± 5 nA
- Offset Voltage: ± 3 mV
- Input Common-Mode Voltage Range Includes GND
- Differential Input Voltage Range Equal to the Power Supply Voltage
- Low Output Saturation Voltage: 250 mV at 4 mA
- Output Voltage Compatible with TTL, DTL, ECL, MOS and CMOS Logic Systems

ADVANTAGES

- High Precision Comparators
- Reduced V_{OS} Drift Over Temperature
- Eliminates Need for Dual Supplies
- Allows Sensing Near GND
- Compatible with All Forms of Logic
- Power Drain Suitable for Battery Operation

Connection Diagrams

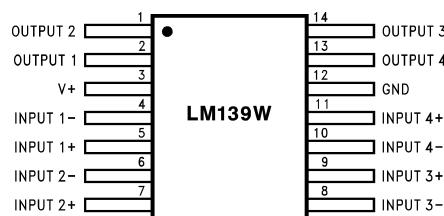


Figure 1. See Package Number NAD0014B

DESCRIPTION

The LM139 consists of four independent precision voltage comparators with an offset voltage specification as low as 2 mV max for all four comparators. These were designed specifically to operate from a single power supply over a wide range of voltages. Operation from split power supplies is also possible and the low power supply current drain is independent of the magnitude of the power supply voltage. These comparators also have a unique characteristic in that the input common-mode voltage range includes ground, even though operated from a single power supply voltage.

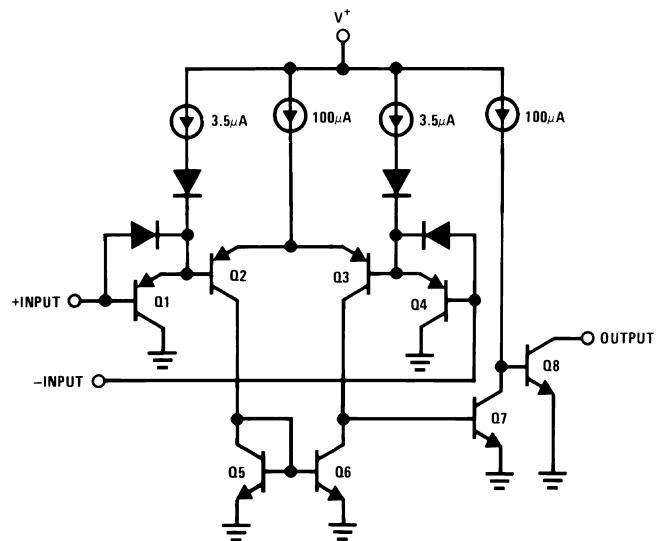
Application areas include limit comparators, simple analog to digital converters; pulse, squarewave and time delay generators; wide range VCO; MOS clock timers; multivibrators and high voltage digital logic gates. The LM139 was designed to directly interface with TTL and CMOS. When operated from both plus and minus power supplies, they will directly interface with MOS logic— where the low power drain of the LM139 is a distinct advantage over standard comparators.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

All trademarks are the property of their respective owners.

Schematic Diagram



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings⁽¹⁾

Supply Voltage, V ⁺⁽²⁾	36 V _{DC} or ± 18 V _{DC}	
Differential Input Voltage ⁽³⁾	36 V _{DC}	
Output Voltage	36 V _{DC}	
Input Voltage	-0.3 V _{DC} to +36 V _{DC}	
Input Current (V _{IN} < -0.3 V _{DC}) ⁽⁴⁾⁽⁵⁾	50 mA	
Power Dissipation ⁽⁶⁾⁽⁷⁾	CLGA	350 mW @ T _A = 125°C
Output Short-Circuit to GND, ⁽⁸⁾	Continuous	
Storage Temperature Range	-65°C \leq T _A \leq +150°C	
Maximum Junction Temperature (T _J)	+175°C	
Lead Temperature (Soldering, 10 seconds)	260°C	
Operating Temperature Range	-55°C \leq T _A \leq +125°C	
Thermal Resistance	θ _{JA}	CLGA (Still Air)
		CLGA (500LF / Min Air flow)
	θ _{JC}	CLGA
Package Weight (typical)	460mg	
ESD rating ⁽⁹⁾	600V	

- (1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not ensure specific performance limits. For ensured specifications and test conditions, see, the Electrical Characteristics. The ensured specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.
- (2) Short circuits from the output to V⁺ can cause excessive heating and eventual destruction. When considering short circuits to ground, the maximum output current is approximately 20mA independent of the magnitude of V⁺
- (3) Positive excursions of input voltage may exceed the power supply level. As long as the other voltage remains within the common-mode range, the comparator will provide a proper output state. The low input voltage state must not be less than -0.3 V_{DC} (or 0.3 V_{DC} below the magnitude of the negative power supply, if used) (at 25°C).
- (4) This input current will only exist when the voltage at any of the input leads is driven negative. It is due to the collector-base junction of the input PNP transistors becoming forward biased and thereby acting as input diode clamps. In addition to this diode action, there is also lateral NPN parasitic transistor action on the IC chip. This transistor action can cause the output voltages of the comparators to go to the V⁺ voltage level (or to ground for a large overdrive) for the time duration that an input is driven negative. This is not destructive and normal output states will re-establish when the input voltage, which was negative, again returns to a value greater than -0.3 V_{DC} (at 25°C).
- (5) The direction of the input current is out of the IC due to the PNP input stage. This current is essentially constant, independent of the state of the output so no loading change exists on the reference or input lines.
- (6) The low bias dissipation and the ON-OFF characteristics of the outputs keeps the chip dissipation very small (P_D \leq 100mW), provided the output transistors are allowed to saturate.
- (7) The maximum power dissipation must be derated at elevated temperatures and is dictated by T_{Jmax} (maximum junction temperature), θ_{JA} (Package junction to ambient thermal resistance), and T_A (ambient temperature). The maximum allowable power dissipation at any temperature is P_{Dmax} = (T_{Jmax} - T_A) / θ_{JA} or the number given in the Absolute Maximum Ratings, whichever is lower.
- (8) Short circuits from the output to V⁺ can cause excessive heating and eventual destruction. When considering short circuits to ground, the maximum output current is approximately 20 mA independent of the magnitude of V⁺.
- (9) Human Body model, 1.5 KΩ in series with 100 pF

Quality Conformance Inspection

Mil-Std-883, Method 5005 - Group A

Subgroup	Description	Temp (°C)
1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125

Quality Conformance Inspection (continued)

Mil-Std-883, Method 5005 - Group A

Subgroup	Description	Temp (°C)
11	Switching tests at	-55

LM139 JAN Electrical Characteristics DC Parameters

The following conditions apply, unless otherwise specified. $-V_{CC} = 0V$

Symbol	Parameters	Conditions	Notes	Min	Max	Unit	Sub-groups
V_{IO}	Input Offset Voltage	$+V_{CC} = 30V, V_O = 15V$		-5.0	5.0	mV	1
				-7.0	7.0	mV	2, 3
		$+V_{CC} = 2V, -V_{CC} = -28V, V_O = -13V$		-5.0	5.0	mV	1
				-7.0	7.0	mV	2, 3
		$+V_{CC} = 5V, V_O = 1.4V$		-5.0	5.0	mV	1
				-7.0	7.0	mV	2, 3
		$+V_{CC} = 2V, -V_{CC} = -3V, V_O = -1.6V$		-5.0	5.0	mV	1
				-7.0	7.0	mV	2, 3
		$+V_{CC} = 30V, R_S = 20K\Omega, V_O = 15V$	See ⁽¹⁾	-25	25	nA	1, 2
			See ⁽¹⁾	-75	75	nA	3
			See ⁽¹⁾	-25	25	nA	1, 2
			See ⁽¹⁾	-75	75	nA	3
			See ⁽¹⁾	-25	25	nA	1, 2
			See ⁽¹⁾	-75	75	nA	3
			See ⁽¹⁾	-25	25	nA	1, 2
			See ⁽¹⁾	-75	75	nA	3
			See ⁽¹⁾	-100	+0.1	nA	1, 2
			See ⁽¹⁾	-200	+0.1	nA	3
$\pm I_{IB}$	Input Bias Current	$+V_{CC} = 30V, R_S = 20K\Omega, V_O = 15V$	See ⁽¹⁾	-100	+0.1	nA	1, 2
			See ⁽¹⁾	-200	+0.1	nA	3
		$+V_{CC} = 2V, -V_{CC} = -28V, R_S = 20K\Omega, V_O = -13V$	See ⁽¹⁾	-100	+0.1	nA	1, 2
			See ⁽¹⁾	-200	+0.1	nA	3
		$+V_{CC} = 5V, R_S = 20K\Omega, V_O = 1.4V$	See ⁽¹⁾	-100	+0.1	nA	1, 2
			See ⁽¹⁾	-200	+0.1	nA	3
		$+V_{CC} = 2V, -V_{CC} = -3V, R_S = 20K\Omega, V_O = -1.6V$	See ⁽¹⁾	-100	+0.1	nA	1, 2
			See ⁽¹⁾	-200	+0.1	nA	3
		$+V_{CC} = 30V, R_S = 20K\Omega, V_O = 15V$	See ⁽¹⁾	-100	+0.1	nA	1, 2
			See ⁽¹⁾	-200	+0.1	nA	3
$CMRR$	Input Voltage Common Mode Rejection	$+V_{CC} = 30V$		76		dB	1, 2, 3
		$+V_{CC} = 5V$		70		dB	1, 2, 3
I_{CEX}	Output Leakage	$+V_{CC} = 30V, V_O = +30V$			1.0	μA	1, 2, 3
$+I_{IL}$	Input Leakage Current	$+V_{CC} = 36V, V + i = 34V, V - i = 0V$		-500	500	nA	1, 2, 3
$-I_{IL}$	Input Leakage Current	$+V_{CC} = 36V, V + i = 0V, V - i = 34V$		-500	500	nA	1, 2, 3
V_{OL}	Logical "0" Output Voltage	$+V_{CC} = 4.5V, I_O = 4mA$		0.4		V	1
				0.7		V	2, 3
		$+V_{CC} = 4.5V, I_O = 8mA$		1.5		V	1
				2.0		V	2, 3
I_{CC}	Power Supply Current	$+V_{CC} = 5V, V_{ID} = 15mV$		2.0		mA	1, 2
				3.0		mA	3
		$+V_{CC} = 30V, V_{ID} = 15mV$		3.0		mA	1, 2
				4.0		mA	3

(1) S/S $R_S = 20K\Omega$, tested at $R_S = 10K\Omega$ as equivalent test.

LM139 JAN Electrical Characteristics DC Parameters (continued)

The following conditions apply, unless otherwise specified. $-V_{CC} = 0V$

Symbol	Parameters	Conditions	Notes	Min	Max	Unit	Sub-groups
$\Delta V_{IO} / \Delta T$	Temperature Coefficient of Input Offset Voltage	$25^{\circ}C \leq T_A \leq 125^{\circ}C$	See ⁽²⁾	-25	25	$\mu V^{\circ}C$	2
		$-55^{\circ}C \leq T_A \leq 25^{\circ}C$	See ⁽²⁾	-25	25	$\mu V^{\circ}C$	3
$\Delta I_{IO} / \Delta T$	Temperature Coefficient of Input Offset Current	$25^{\circ}C \leq T_A \leq 125^{\circ}C$	See ⁽²⁾	-300	300	$pA^{\circ}C$	2
		$-55^{\circ}C \leq T_A \leq 25^{\circ}C$	See ⁽²⁾	-400	400	$pA^{\circ}C$	3
A_{VS}	Open Loop Voltage Gain	$+V_{CC} = 15V, R_L = 15K\Omega, 1V \leq V_O \leq 11V$	See ⁽³⁾	50		V/mV	4
			See ⁽³⁾	25		V/mV	5, 6
V_{IO}	Tempco Screen				4.0	mV	
CMRR	Tempco Screen				70	dB	
I_{IO}	Tempco Screen				13	nA	
I_{IB}	Tempco Screen				12	nA	

(2) Calculated parameter; for Delta V_{IO} / Delta T use V_{IO} test at $+V_{CC} = 30V, -V_{CC} = 0V, V_O = 15V$; and for Delta I_{IO} / Delta T use I_{IB} test at $+V_{CC} = 30V, -V_{CC} = 0V, V_O = 15V$

(3) Datalog of $K = V/mV$.

LM139 JAN Electrical Characteristics AC Parameters

Symbol	Parameters	Conditions	Notes	Min	Max	Unit	Sub-groups
t _{RLH}	Response Time: Low-to-High	+V _{CC} = 5V, V _I = 100mV, R _L = 5.1KΩ, V _{OD} = 5mV		5.0	μS	7, 8B	
				7.0	μS	8A	
		+V _{CC} = 5V, V _I = 100mV, R _L = 5.1KΩ, V _{OD} = 50mV		0.8	μS	7, 8B	
				1.2	μS	8A	
t _{RHL}	Response Time: High-to-Low	+V _{CC} = 5V, V _I = 100mV, R _L = 5.1KΩ, V _{OD} = 5mV		2.5	μS	7, 8B	
				3.0	μS	8A	
		+V _{CC} = 5V, V _I = 100mV, R _L = 5.1KΩ, V _{OD} = 50mV		0.8	μS	7, 8B	
				1.0	μS	8A	
C _S	Channel Separation	+V _{CC} = 20V, -V _{CC} = -10V, A to B		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, A to C		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, A to D		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, B to A		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, B to C		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, B to D		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, C to A		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, C to B		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, C to D		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, D to A		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, D to B		80		dB	7
		+V _{CC} = 20V, -V _{CC} = -10V, D to C		80		dB	7
V _{LAT}	Voltage Latch (Logical "1" Input)	+V _{CC} = 5V, V _I = 10V, I _O = 4mA			0.4	V	9

LM139 JAN Electrical Characteristics DC Parameters Drift Values

The following conditions apply, unless otherwise specified. –V_{CC} = 0V

Delta calculations performed on JAN S product at Group B, Subgroup 5.

Symbol	Parameters	Conditions	Notes	Min	Max	Unit	Sub-groups
V _{IO}	Input Offset Voltage	V _{CC} = 30V, V _O = 15V		-1.0	1.0	mV	1
±I _{Bias}	Input Bias Current	V _{CC} = 30V, R _S = 20KΩ, V _O = 15V		-15	15	nA	1

Typical Performance Characteristics

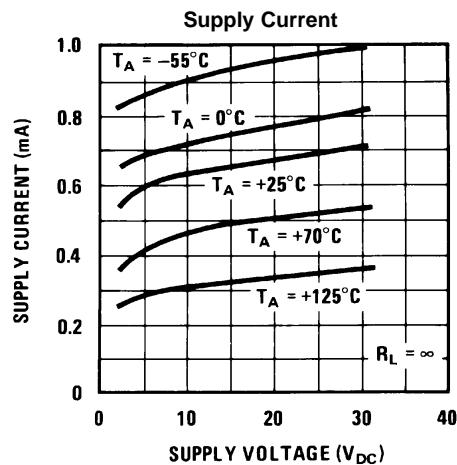


Figure 2.

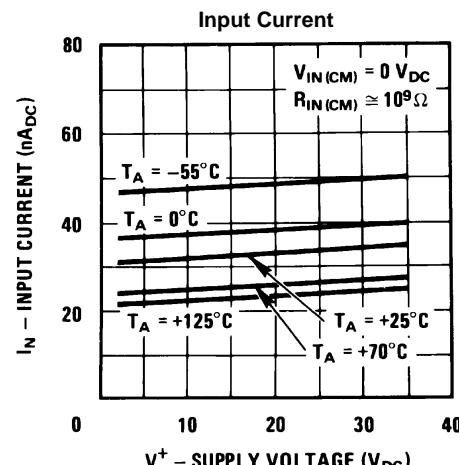


Figure 3.

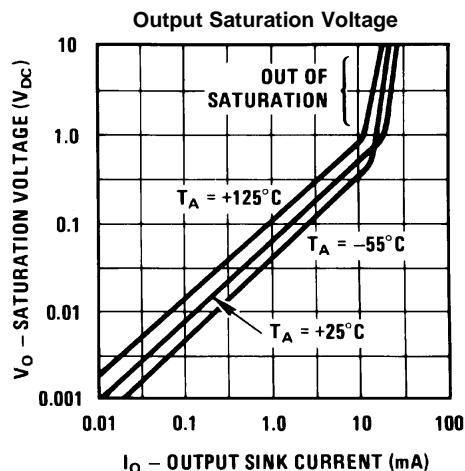


Figure 4.

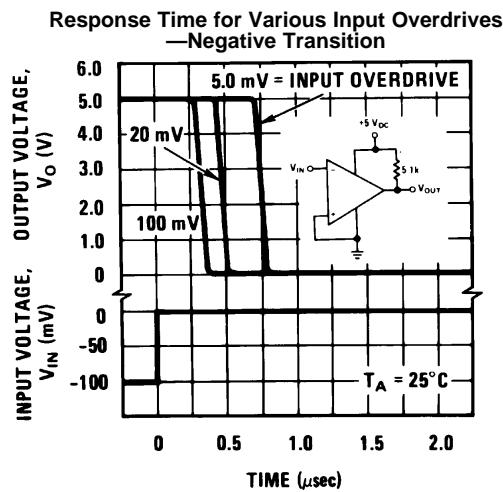


Figure 5.

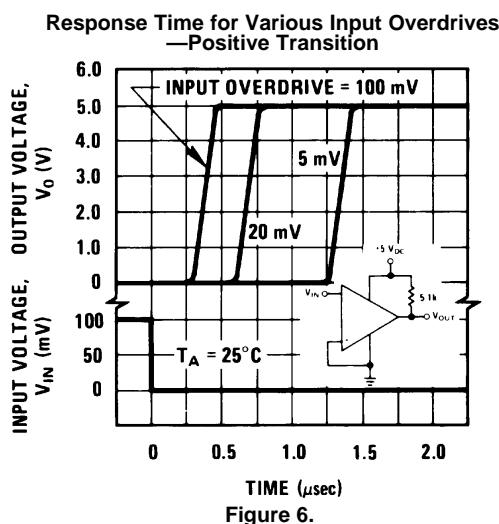


Figure 6.

APPLICATION HINTS

The LM139 is a high gain, wide bandwidth device which, like most comparators, can easily oscillate if the output lead is inadvertently allowed to capacitively couple to the inputs via stray capacitance. This shows up only during the output voltage transition intervals as the comparator changes states. Power supply bypassing is not required to solve this problem. Standard PC board layout is helpful as it reduces stray input-output coupling. Reducing the input resistors to $< 10\text{ k}\Omega$ reduces the feedback signal levels and finally, adding even a small amount (1 to 10 mV) of positive feedback (hysteresis) causes such a rapid transition that oscillations due to stray feedback are not possible. Simply socketing the IC and attaching resistors to the pins will cause input-output oscillations during the small transition intervals unless hysteresis is used. If the input signal is a pulse waveform, with relatively fast rise and fall times, hysteresis is not required.

All pins of any unused comparators should be tied to the negative supply.

The bias network of the LM139 establishes a drain current which is independent of the magnitude of the power supply voltage over the range of from 5 V_{DC} to 30 V_{DC} .

It is usually unnecessary to use a bypass capacitor across the power supply line.

The differential input voltage may be larger than V^+ without damaging the device. Protection should be provided to prevent the input voltages from going negative more than $-0.3\text{ V}_{\text{DC}}$ (at 25°C). An input clamp diode can be used as shown in the applications section.

The output of the LM139 is the uncommitted collector of a grounded-emitter NPN output transistor. Many collectors can be tied together to provide an output OR'ing function. An output pull-up resistor can be connected to any available power supply voltage within the permitted supply voltage range and there is no restriction on this voltage due to the magnitude of the voltage which is applied to the V^+ terminal of the LM139 package. The output can also be used as a simple SPST switch to ground (when a pull-up resistor is not used). The amount of current which the output device can sink is limited by the drive available (which is independent of V^+) and the β of this device. When the maximum current limit is reached (approximately 16 mA), the output transistor will come out of saturation and the output voltage will rise very rapidly. The output saturation voltage is limited by the approximately $60\Omega R_{\text{SAT}}$ of the output transistor. The low offset voltage of the output transistor (1 mV) allows the output to clamp essentially to ground level for small load currents.

Typical Applications

($V^+ = 5.0\text{ V}_{\text{DC}}$)

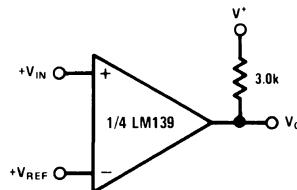


Figure 7. Basic Comparator

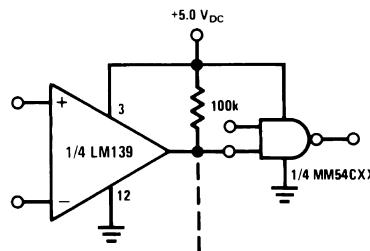
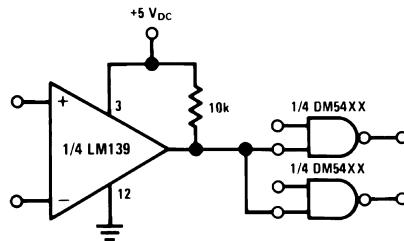
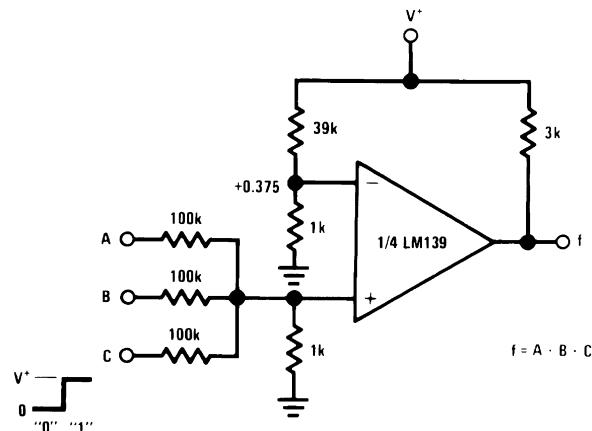
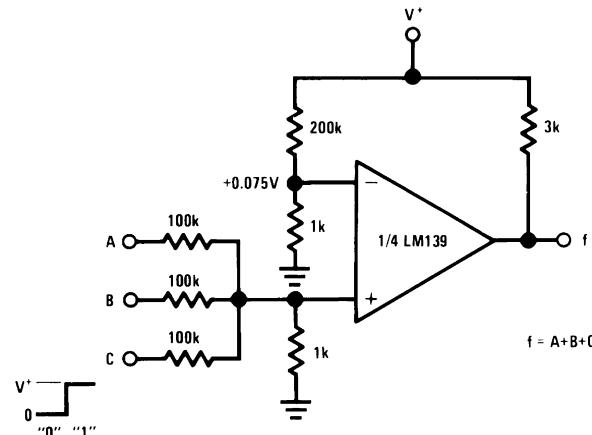
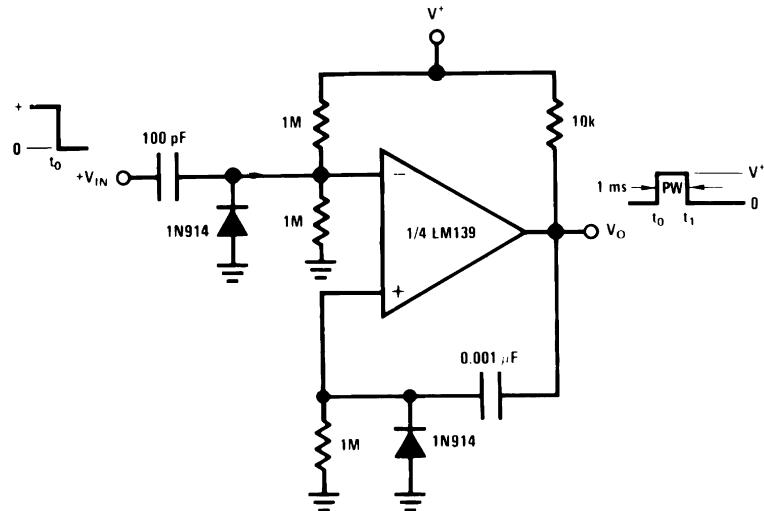
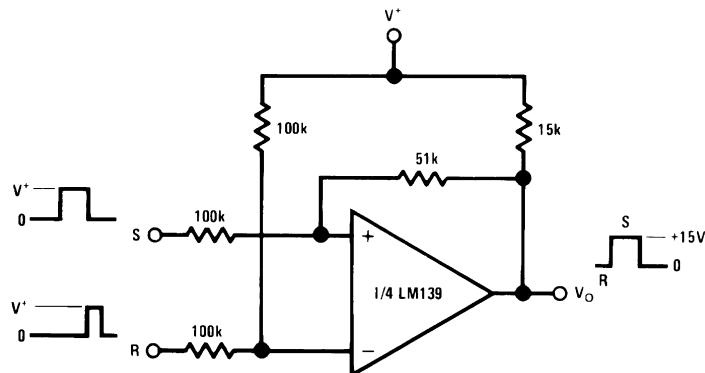


Figure 8. Driving CMOS


Figure 9. Driving TTL

Figure 10. AND Gate

Figure 11. OR Gate

Typical Applications $(V^+ = 15 \text{ V}_{\text{DC}})$ **Figure 12. One-Shot Multivibrator****Figure 13. Bi-Stable Multivibrator**

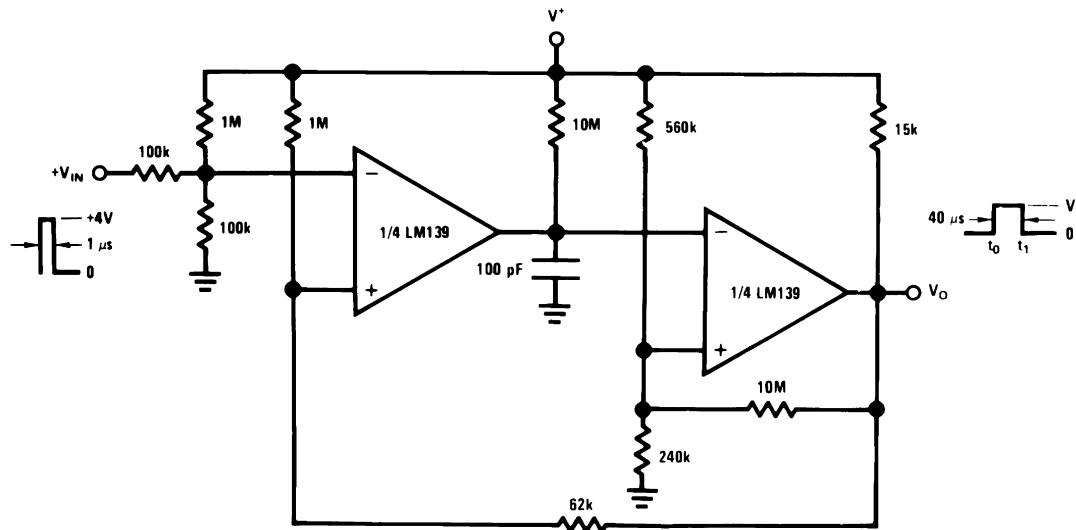


Figure 14. One-Shot Multivibrator with Input Lock Out

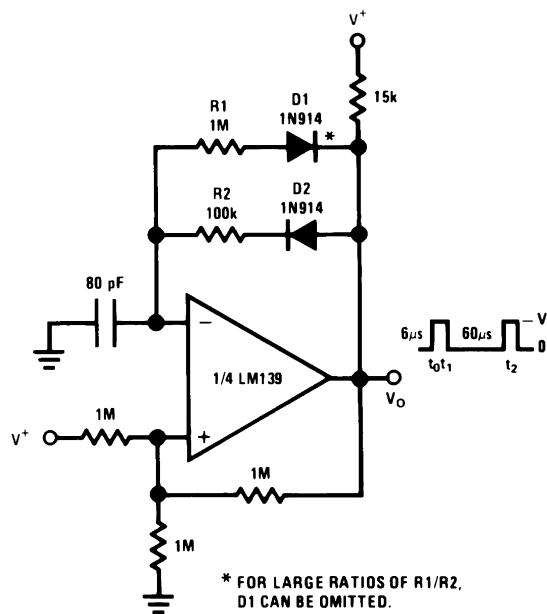


Figure 15. Pulse Generator

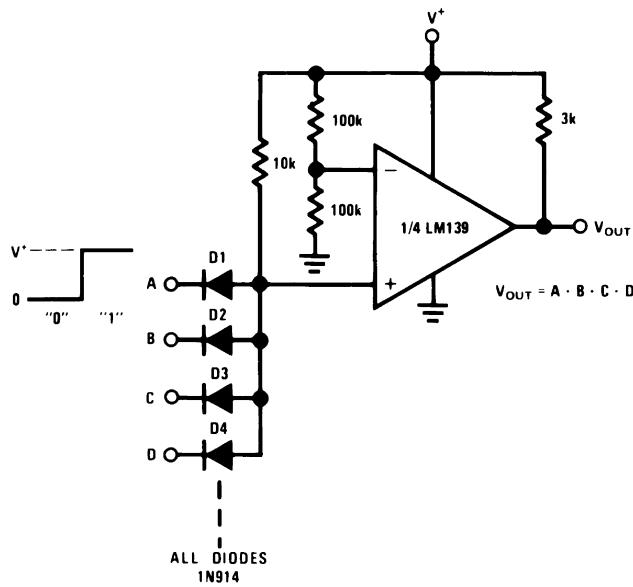


Figure 16. Large Fan-In AND Gate

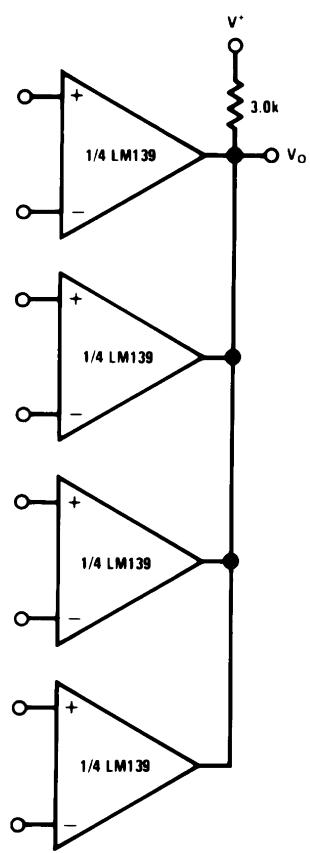
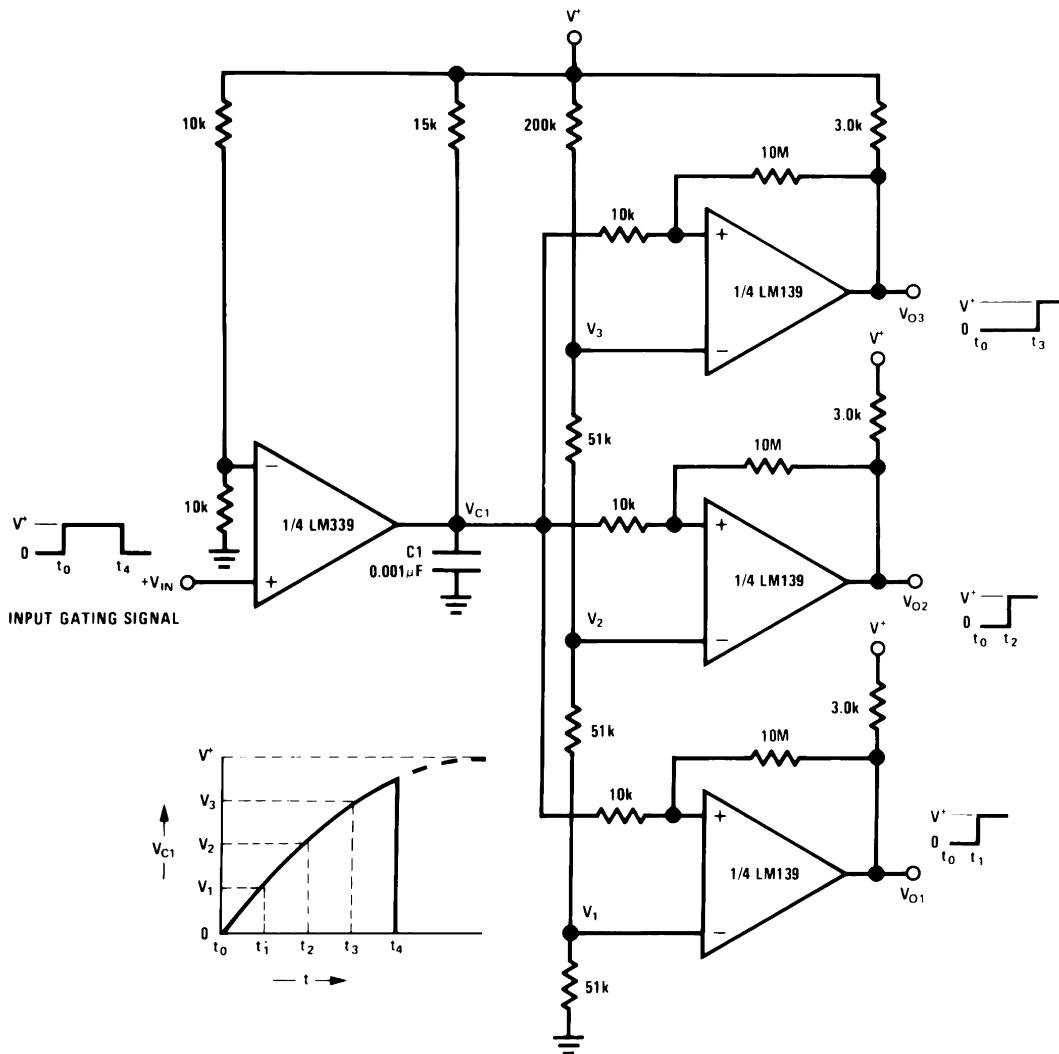
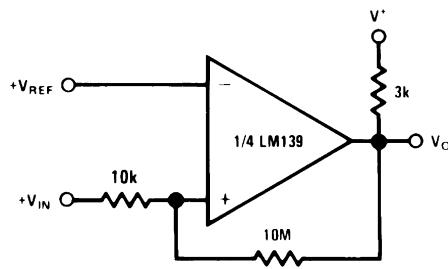
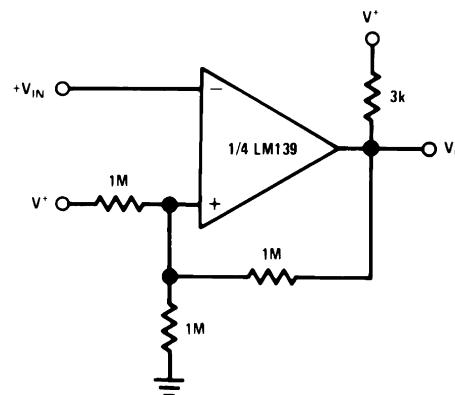


Figure 17. ORing the Outputs


Figure 18. Time Delay Generator

Figure 19. Non-Inverting Comparator with Hysteresis

Figure 20. Inverting Comparator with Hysteresis

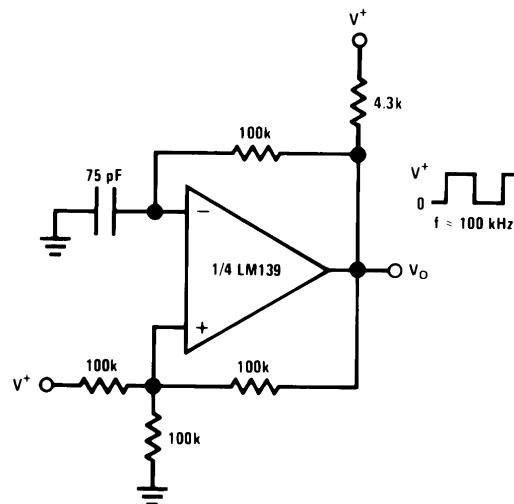


Figure 21. Squarewave Oscillator

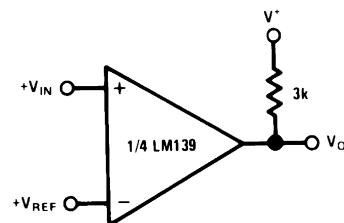


Figure 22. Basic Comparator

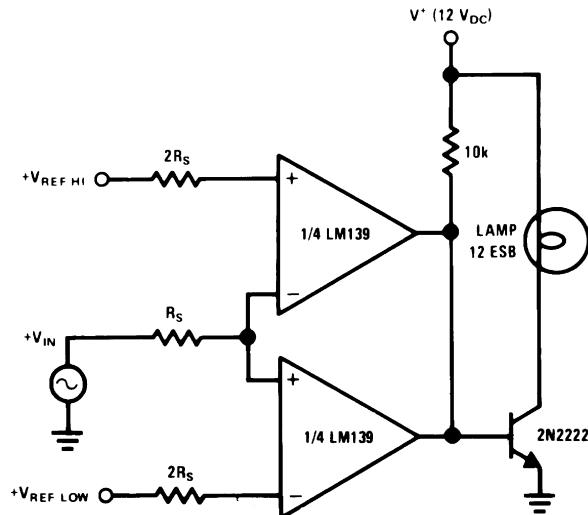


Figure 23. Limit Comparator

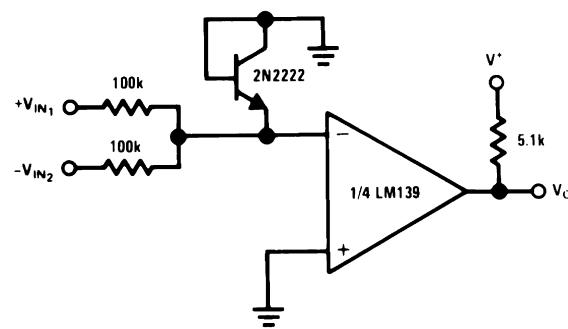
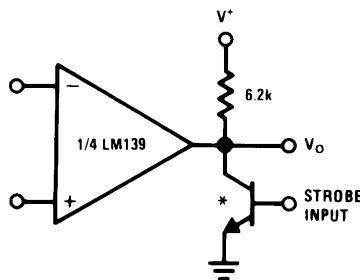


Figure 24. Comparing Input Voltages of Opposite Polarity



* Or open-collector logic gate without pull-up resistor

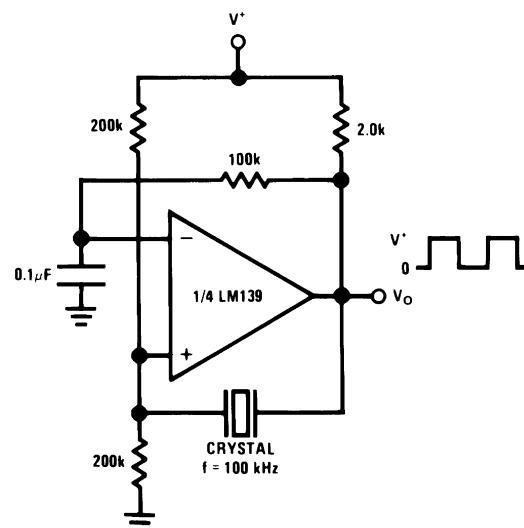


Figure 25. Output Strobing

Figure 26. Crystal Controlled Oscillator

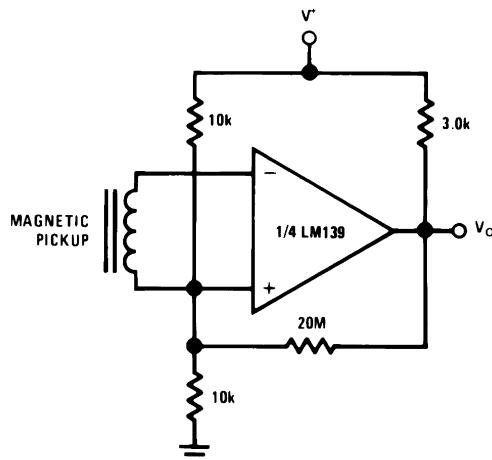


Figure 27. Transducer Amplifier

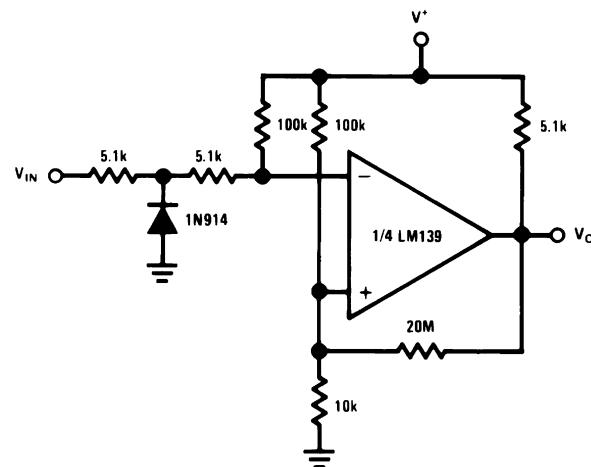
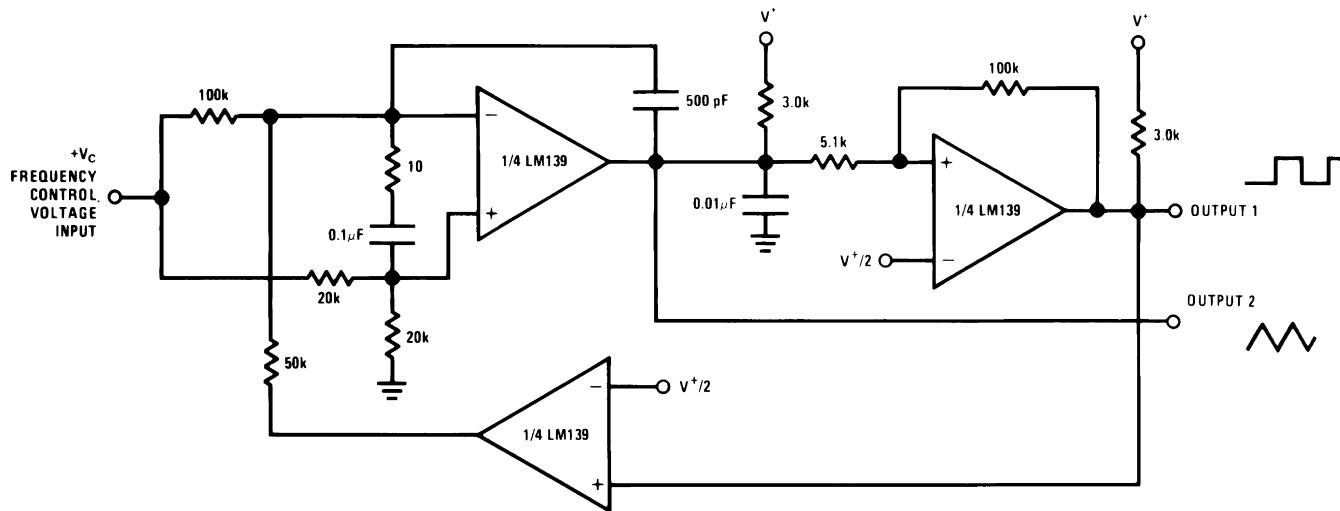


Figure 28. Zero Crossing Detector (Single Power Supply)



$V^+ = +30 \text{ V}_{\text{DC}}$
 $250 \text{ mV}_{\text{DC}} \leq V_C \leq +50 \text{ V}_{\text{DC}}$
 $700 \text{ Hz} \leq f_O \leq 100 \text{ kHz}$

Figure 29. Two-Decade High-Frequency VCO

Split-Supply Applications

($V^+ = +15 \text{ V}_{\text{DC}}$ and $V^- = -15 \text{ V}_{\text{DC}}$)

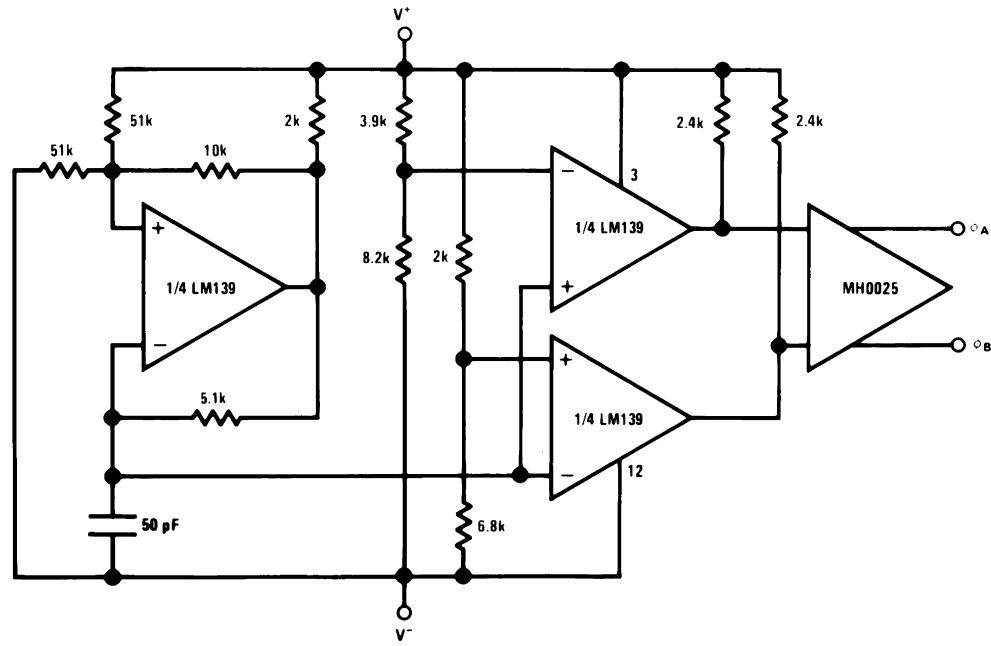


Figure 30. MOS Clock Driver

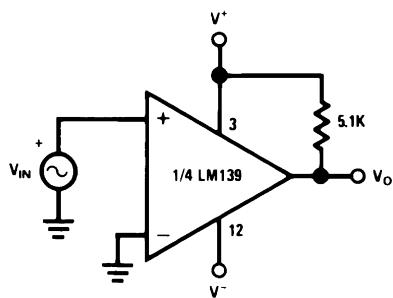


Figure 31. Zero Crossing Detector

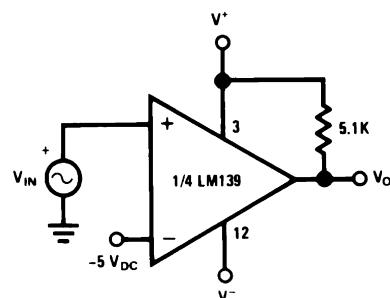


Figure 32. Comparator With a Negative Reference

REVISION HISTORY

Date Released	Revision	Section	Changes
02/15/05	A	New Release to corporate format	1 MDS datasheet converted into Corp. datasheet format. MJLM139-X rev 0D0. MDS datasheet will be archived.
10/26/2010	B	Order Information, Connection Diagrams, Absolute Ratings, Physical Dimensions drawings,	Update with current device information and format. Deleted J and WG pkg references. Revision A will be Archived
03/20/2013	B	All	Changed layout of National Data Sheet to TI format

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
JL139BDA	Active	Production	CFP (NAD) 14	19 TUBE	No	SNPB	Level-1-NA-UNLIM	-55 to 125	JL139BDA Q JM38510/ 11201BDA ACO 11201BDA >T
JL139BDA.B	Active	Production	CFP (NAD) 14	19 TUBE	No	SNPB	Level-1-NA-UNLIM	-55 to 125	JL139BDA Q JM38510/ 11201BDA ACO 11201BDA >T
JM38510/11201BDA	Active	Production	CFP (NAD) 14	19 TUBE	No	SNPB	Level-1-NA-UNLIM	-55 to 125	JL139BDA Q JM38510/ 11201BDA ACO 11201BDA >T
M38510/11201BDA	Active	Production	CFP (NAD) 14	19 TUBE	No	SNPB	Level-1-NA-UNLIM	-55 to 125	JL139BDA Q JM38510/ 11201BDA ACO 11201BDA >T

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

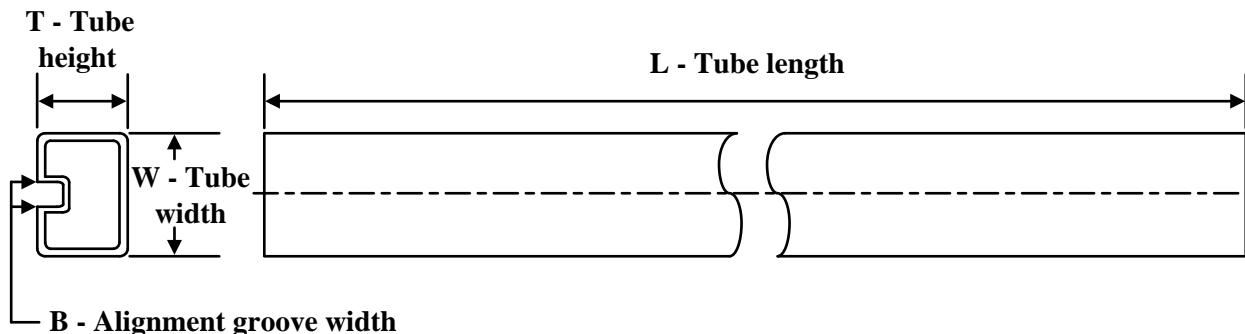
⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

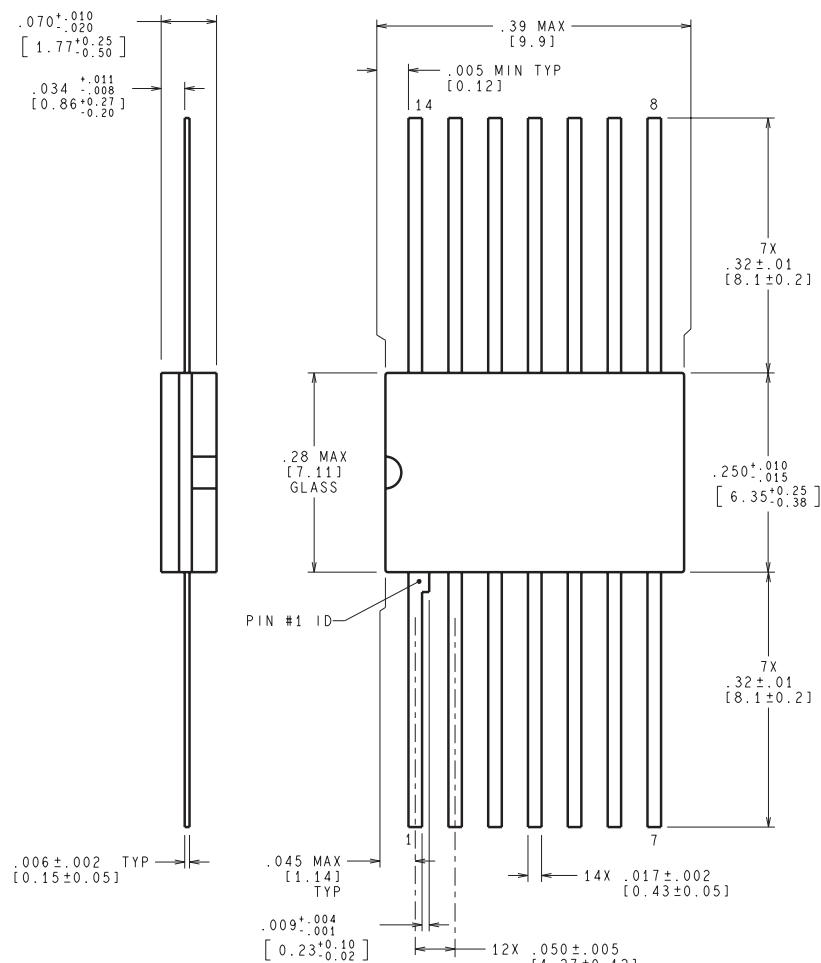
TUBE


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
JL139BDA	NAD	CFP	14	19	502	23	9398	9.78
JL139BDA.B	NAD	CFP	14	19	502	23	9398	9.78
JM38510/11201BDA	NAD	CFP	14	19	502	23	9398	9.78
M38510/11201BDA	NAD	CFP	14	19	502	23	9398	9.78

MECHANICAL DATA

NAD0014B



W14B (Rev P)

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to [TI's Terms of Sale](#), [TI's General Quality Guidelines](#), or other applicable terms available either on [ti.com](#) or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2026, Texas Instruments Incorporated

Last updated 10/2025